

Chipsmall Limited consists of a professional team with an average of over 10 year of expertise in the distribution of electronic components. Based in Hongkong, we have already established firm and mutual-benefit business relationships with customers from, Europe, America and south Asia, supplying obsolete and hard-to-find components to meet their specific needs.

With the principle of "Quality Parts, Customers Priority, Honest Operation, and Considerate Service", our business mainly focus on the distribution of electronic components. Line cards we deal with include Microchip, ALPS, ROHM, Xilinx, Pulse, ON, Everlight and Freescale. Main products comprise IC, Modules, Potentiometer, IC Socket, Relay, Connector. Our parts cover such applications as commercial, industrial, and automotives areas.

We are looking forward to setting up business relationship with you and hope to provide you with the best service and solution. Let us make a better world for our industry!



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2SK3372G

Silicon N-Channel Junction FET

For impedance conversion in low frequency For electret capacitor microphone

■ Features

- High mutual conductance g_m
- Low noise voltage NV

■ Absolute Maximum Ratings T_a = 25°C

Parameter	Symbol	Rating	Unit	
Drain-source voltage (Gate open)	V _{DSO}	20	V	
Gate-drain voltage (Source open)	V_{GDO}	20	V	
Drain-source current (Gate open)	I_{DSO}	2	mA	
Gate-drain current (Source open)	I_{GDO}	2	mA	
Gate-source current (Drain open)	I_{GSO}	2	mA	
Power dissipation	P _D	100	mW	
Operating ambient temperature	T _{opr}	-20 to +80	°C	
Storage temperature	T _{stg}	-55 to +125	°C °C	

Package

- Code SSSMini3-F2
- Pin Name
 - 1: Drain
 - 2: Source
 - 3: Gate
- Marking Symbol: 1H

■ Electrical Characteristics $T_a = 25^{\circ}C \pm 3^{\circ}C$

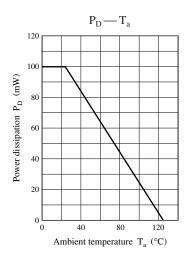
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Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Drain current *1	I_D	$V_{DS} = 2.0 \text{ V}, R_D = 2.2 \text{ k}\Omega \pm 1\%$	100	0/1/2	470	μΑ
Drain-source current	I_{DSS}	$V_{DS} = 2.0 \text{ V}, R_D = 2.2 \text{ k}\Omega \pm 1\%, V_{GS} = 0$	107	85	460	μΑ
Mutual conductance	g _m	$V_D = 2.0 \text{ V}, V_{GS} = 0, f = 1 \text{ kHz}$	660	1600		μS
Noise voltage	NV	$V_D = 2.0 \text{ V}, R_D = 2.2 \text{ k}\Omega \pm 1\%$ $C_O = 5 \text{ pF}, A\text{-Curve}$			4	μV
Voltage gain	G _{V1}	$V_D = 2.0 \text{ V}, R_D = 2.2 \text{ k}\Omega \pm 1\%$ $C_O = 5 \text{ pF}, e_G = 10 \text{ mV}, f = 1 \text{ kHz}$	-7.5	-4.7		dB
	G_{V2}	$V_D = 12 \text{ V}, R_D = 2.2 \text{ k}\Omega \pm 1\%$ $C_O = 5 \text{ pF}, e_G = 10 \text{ mV}, f = 1 \text{ kHz}$	-4.0	-1.5		
	G _{V3}	$V_D = 1.5 \text{ V}, R_D = 2.2 \text{ k}\Omega \pm 1\%$ $C_O = 5 \text{ pF}, e_G = 10 \text{ mV}, f = 1 \text{ kHz}$	-8.0	-5.0		
	$\Delta G_{V}.f ^{*2}$	$V_D = 2.0 \text{ V}, R_D = 2.2 \text{ k}\Omega \pm 1\%$ $C_O = 5 \text{ pF}, e_G = 10 \text{ mV}, f = 1 \text{ kHz to } 70 \text{ Hz}$		0	1.7	
Voltage gain difference	$ G_{V2}-G_{V1} $		0		4.0	dB
	$ G_{V1}-G_{V3} $		0		1.7	

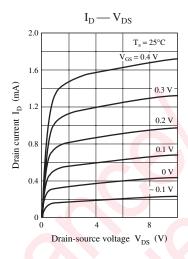
Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

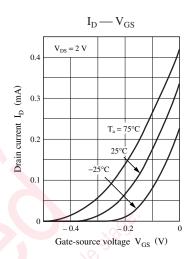
Publication date: May 2008 SJF00066BED 1

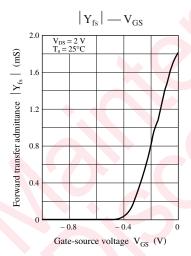
^{2. *1:} I_D is assured for I_{DSS}.

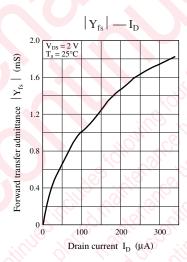
^{*2:} Δ | G_V . f | is assured for AQL 0.065%. (The measurement method is used by source-grounded circuit.)







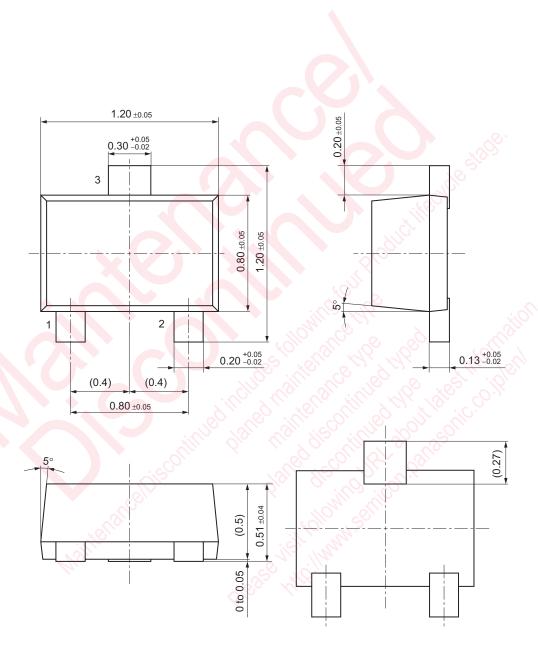




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SSSMini3-F2





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